- Inputs Are TTL-Voltage Compatible
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- **Package Options Include Plastic** Small-Outline (D), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPS

description

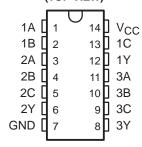
The 'ACT11 contain three independent 3-input AND gates. The devices perform the Boolean functions $Y = A \cdot B \cdot C$ or $Y = \overline{A} + \overline{B} + \overline{C}$ in positive logic.

The SN54ACT11 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ACT11 is characterized for operation from -40°C to 85°C.

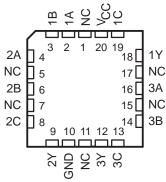
FUNCTION TABLE (each gate)

	INPUTS		OUTPUT
Α	В	С	Υ
Н	Н	Н	Н
L	X	Χ	L
Х	L	Χ	L
Х	Χ	L	L

SN54ACT11 . . . J OR W PACKAGE SN74ACT11 . . . D, DB, N, OR PW PACKAGE (TOP VIEW)

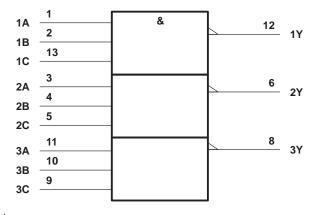


SN54ACT11 ... FK PACKAGE (TOP VIEW)

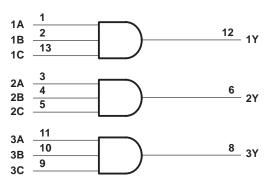


NC - No internal connection

logic symbol†



logic diagram, each gate (positive logic)



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, DB, J, N, PW, and W packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V _{CC} or GND	±200 mA
Maximum power dissipation at T _A = 55°C (in still air) (see Note 2)): D package 1.25 W
	DB package 0.5 W
	N package 1.1 W
	PW package 0.5 W
Storage temperature range, T _{Stg}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions (see Note 3)

		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
VO	Output voltage	0	VCC	0	VCC	V
IOH	High-level output current		-24		-24	mA
lOL	Low-level output current		24		24	mA
Δt/Δν	Input transition rise or fall rate	0	8	0	8	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T _A = 25°C			SN54ACT11		SN74ACT11		UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
VOH	ΙΟΗ = – 50 μΑ	4.5 V	4.4	4.49		4.4		4.4		$[\]$	
		5.5 V	5.4	5.49		5.4		5.4			
	lou - 24 mA	4.5 V	3.86			3.7		3.76		V	
	I _{OH} = - 24 mA	5.5 V	4.86			4.7		4.76		v	
	I _{OH} = - 50 mA [†]	5.5 V				3.85					
	I _{OH} = - 75 mA [†]	5.5 V						3.85			
Ver	Ι _{ΟL} = 50 μΑ	4.5 V		0.001	0.1		0.1		0.1	V	
		5.5 V		0.001	0.1		0.1		0.1		
	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44		
VOL		5.5 V			0.36		0.5		0.44		
	I _{OL} = 50 mA [†]	5.5 V					1.65				
	I _{OL} = 75 mA [†]	5.5 V							1.65		
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ	
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		40		20	μΑ	
Δl _{CC} ‡	One input at 3.4 V, Other inputs at GND or V _{CC}	5.5 V		0.6			1.6		1.5	mA	
C _i	VI = V _{CC} or GND	5 V		2.6						pF	

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	T _A = 25°C			SN54ACT11		SN74ACT11		UNIT
PARAMETER	(INPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	Any	Y	1.5	6	9.5	1	10.5	1	10.5	ns I
t _{PHL}			1.5	6	9.5	1	10.5	1	10.5	

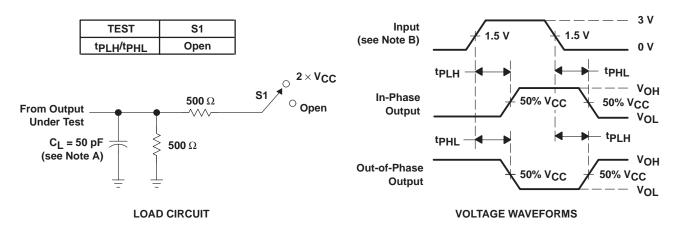
operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 1 \text{ MHz}$	20	pF



[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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